

Lecture 19: Biasing

• Announcements:

- HW#6 online and due Friday Oct. 12 via Gradescope
- PreLab#4 is online and due next week, as is Lab#3
- Lab#4 (the experimental part) will be online soon
- Midterm 1: Later today, Friday, Oct. 5, from 5-6:30 p.m., in 277 Cory
- Midterm Info Sheet online with updates from what we discussed last week

• Lecture Topics:

- ↳ BJT IV Curves
- ↳ Parameter Independent Biasing for Discrete BJT's
- ↳ Discrete MOS Biasing

• Last Time:

- BJT biasing examples using approximations

IV Characteristics of BJT's

$i_C = I_S \exp\left(\frac{V_{BE}}{V_T}\right)$

(a diode-like characteristic)

⇒ often more interested in $i_C = f(i_B, V_{CE})$:
 (get curves similar to MOS case)

Forward-Active

Saturation

increasing i_B

i_{B4}
 i_{B3}
 i_{B2}
 i_{B1}

Finite Slope: $\frac{1}{V_A}$

Early Voltage $\cong V_A$

$i_C = \left[I_S \exp\left(\frac{V_{BE}}{V_T}\right) \right] \left[1 + \frac{V_{CE}}{V_A} \right]$

↳ Why V_{CE} ? $V_{CE} = V_{CB} + V_{BE}$
 diode turn-on = constant
 reverse-bias across BCJ $\rightarrow \Delta V_{CE} \uparrow \cong \Delta V_{CB} \uparrow$

What happens physically?

x_1 = depl. region width at B-CJ for $N_{CE1} = N_{CE1}$
 x_2 = " " " " " for $N_{CE} = N_{CE2}$ x_1

① Case: $N_{CE1} \rightarrow x_1 \rightarrow i_{C1} \propto \text{slope of this line}$

② Case: increase N_{CE} : $N_{CE} \rightarrow N_{CE2}$ ($N_{CE1} < N_{CE2}$)
 $N_{CE} \uparrow \rightarrow x \uparrow \rightarrow x_1 \rightarrow x_2 \rightarrow i_{C2} \propto \text{slope of this line}$
 ($x_2 > x_1$) $\therefore i_{C2} > i_{C1}$

Thus: $N_{CE} \uparrow \rightarrow i_C \uparrow$ due to $x_{BC} \text{ depl} \uparrow$

Result: $i_C = f(i_B, N_{CE})$ in forward-active!

$$i_C = I_S \exp\left(\frac{V_{BE}}{V_T}\right) \left[1 + \frac{N_{CE}}{N_A}\right]$$

Parameter-Independent Biasing for Discrete BJTs

- \Rightarrow behavior of an analog ckt. depends heavily on its DC operating pt. (or DC Bias Point)
 - \Rightarrow for BJTs, I_C is most important
 - \Rightarrow must insure that I_C is stable against variations in $\beta, V_{BE}, \frac{1}{2} I_S$
 - ① β is hard to control \rightarrow varies from process to process
 - ② I_S " " " " \rightarrow
 - ③ $V_{BE} = \frac{KT}{q} \ln\left(\frac{I_C}{I_S}\right) \rightarrow$ depends on $T \text{ \& } I_S$
 - ④ $V_T = \frac{KT}{q} \rightarrow$ depends on T
- \Rightarrow need biasing strategies that suppress dependence on these

Compare Some Biasing Strategies

① Voltage Sources and R_C :

$I_C = I_S \exp\left(\frac{V_{BE}}{V_T}\right) = I_S \exp\left(\frac{V_{BB}}{V_T}\right)$

must be very precisely set! X

Varies directly w/ I_S X exponential w/ V_T X

\therefore strong dependence on $I_S, V_T \rightarrow$ NOT GOOD!
(plus, we don't normally have a V_{BB} in integrated ckt's ... just V_{CC})

② Base Resistor to V_{CC}

$I_B = \frac{V_{CC} - V_{BE(on)}}{R_B}$

$I_C = \beta I_B = \frac{V_{CC} - V_{BE(on)}}{R_B/\beta}$

less dependence on V_T & I_S when $V_{CC} \gg V_{BE}$ BETTER!

heavily dependent on β ! X
NOT GOOD!

③ Base Resistor to V_{CC} Plus Emitter Resistor:

Apply KVL: $V_{CC} = I_B R_B + V_{BE} + I_E R_E$

$= \frac{I_C}{\beta} R_B + V_{BE} + \frac{I_C}{\alpha} R_E$

$I_C = \frac{V_{CC} - V_{BE}}{\frac{R_E}{\alpha} + \frac{R_B}{\beta}}$

For stability against ΔV_{BE} : Choose $V_{CC} \gg V_{BE}$

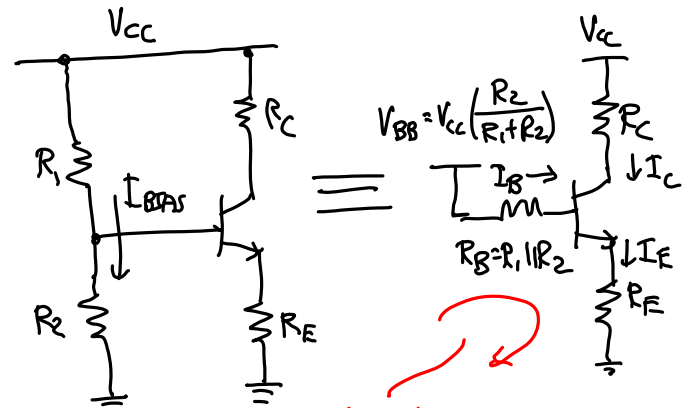
For stability against $\Delta \beta$: Need $\frac{R_E}{\alpha} \gg \frac{R_B}{\beta}$

e.g., $\frac{R_E}{\alpha} \gg 10 \frac{R_B}{\beta}$ is a good choice!

\Rightarrow Problem: To get needed I_B , need large R_B

\Rightarrow reduce R_B by reducing voltage applied across it... needed

④ Standard Parameter Independent Biasing:
(for discrete BJT ccts, as opposed to IC's)



voltage divider

Apply KVL:

$$I_C = \frac{V_{BB} - V_{BE}}{\frac{R_E}{\alpha} + \frac{R_B}{\beta}}$$

Thus, for bias stability, want:

- ① $V_{BB} \gg V_{BE}$ → for insensitivity to V_{BE}
- ② $\frac{R_E}{\alpha} \gg \frac{R_B}{\beta}$ → for insensitivity to β
rule of thumb: $\frac{R_E}{\alpha} \geq 10 \frac{R_B}{\beta}$
want $R_B = \text{small} \rightarrow R_1, R_2 \text{ small}$
- ③ $I_{B_{bias}} \geq 10 I_B$
want $\beta = \text{large} \rightarrow I_B = \text{small}$
 $I_{B_{bias}} = \text{large}$

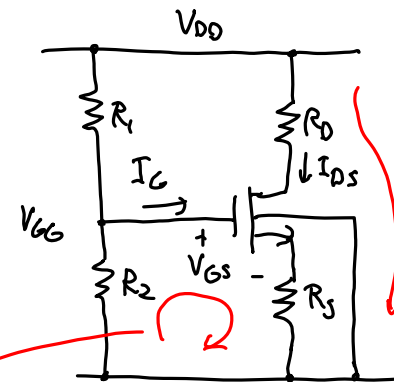
For practical amplification requirements: compromise:

- ① $V_{BB} \approx \frac{1}{3} V_{CC}$
- ② $V_{CE} \approx \frac{1}{3} V_{CC}$
- ③ $V_{R_E} = I_E R_E \approx \frac{1}{3} V_{CC}$
- ④ $0.1 I_E < I_{B_{bias}} < I_E$

Good starting pt.
... but not rules!
↓
must adjust for a given design

MOS Biasing

⇒ can use a similar biasing strategy for discrete MOS ccts.



KVL: $V_{GG} = V_{DD} \left(\frac{R_2}{R_1 + R_2} \right)$, $I_G = 0 \rightarrow V_G = V_{GG}$

KVL: $V_{GG} = V_{GS} + I_{DS} R_S$ (2)

KVL: $V_{DD} = I_{DS} R_D + V_{DS} + I_{DS} R_S + V_{SS}$ (1)

To find the DC operating point: (by hand)

① Assume saturation:

can often neglect

$$I_{DS} = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_t)^2 (1 + \lambda V_{DS})$$

$$\text{w/ } V_t = f(V_{SB}) = V_{t0} + \gamma (\sqrt{2\phi_f - V_{SB}} - \sqrt{2\phi_f})$$

$$\Rightarrow \text{using (2): } V_{GS} = V_{DS} + \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_t)^2 R_S \quad (3)$$

② Solve for V_{DS} assuming $V_t = V_{t0}$.

③ $V_S = V_{GS} - V_{DS} \rightarrow V_{SB} = V_S - V_{SS} \rightarrow$ find $V_t(V_{SB}) = V_t'$

④ Plug $V_t' = V_t(V_{SB})$ into (3) \rightarrow Get V_{GS}'

⑤ Back to ③ \rightarrow iterate to convergence

⋮

⑥ Check operating pt. \rightarrow saturated?

if yes \rightarrow done

if no \rightarrow assume linear & start over

\Rightarrow tedious, but effective for discrete (i.e., off-chip) MOS ckt.

\Rightarrow on-chip, we generally use current mirrors...